

Search Notes

Application/Control No.

10/828,262

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

HATA ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	735 - 737, 706, 707, 711 & 276	4/13/2005	C.C.
257	780 & 781	4/13/2005	C.C.
257	783 & 772	4/13/2005	C.C.
257	787 & 713	4/13/2005	C.C.
257	775 & 341	4/13/2005	C.C.
257	796	4/13/2005	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	4/13/2005	C.C.
Consulted with S. Clark 257/735 - 737, 706, 707, 711, 276, 780, 781, 783, 772 & 787 word: source, gate, lead, beam, heat sink	4/12/2005	C.C.
Consulted with J. Jackson 257/713, 775, 341, 796	4/12/2005	C.C.